

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)				Docket No. AMAT/5163P1/DISP LAY/AHRDWR/RKK	Serial No. 10/321,289		
LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT				Applicant Kim, et al.	Confirmation No.: 2911		
(Use several sheets if necessary)				Filing Date	Group		
	Examiner	FEB 03 2004 PATENT & TRADEMARK OFFICE		December 17, 2002	3742		
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*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
<i>Sk</i>	A1	4,486,487	12/04/84	Skarp	428	216	04/25/1983
	A2	4,767,494	08/30/88	Kobayashi et al.	156	606	09/19/1986
	A3	4,806,321	02/21/89	Nishizawa et al.	422	245	07/21/1985
	A4	4,813,846	03/21/89	Helms	414	744.1	04/29/87
	A5	4,829,022	05/09/89	Kobayashi et al.	437	107	12/09/1986
	A6	4,838,983	06/13/89	Schumaker et al.	156	613	03/18/1988
	A7	4,838,993	06/13/89	Aoki et al.	156	643	12/03/1987
	A8	4,840,921	06/20/89	Matsumoto	437	89	06/30/1988
	A9	4,845,049	07/04/89	Sunakawa	437	81	03/28/1988
	A10	4,859,625	08/22/89	Nishizawa et al.	437	81	11/20/1987
	A11	4,859,627	08/22/89	Sunakawa	437	81	07/01/1988
	A12	4,861,417	08/29/89	Mochizuki et al.	156	610	03/24/1988
	A13	4,876,218	10/24/89	Pessa et al.	437	107	09/26/1988
	A14	4,917,556	04/17/90	Stark et al.	414	217	05/26/89
	A15	4,927,670	05/22/1990	Erbil	427	255.3	06/22/1988
	A16	4,931,132	06/05/90	Aspnes et al.	156	601	10/07/1988
	A17	4,951,601	08/28/90	Maydan, et al.	118	719	06/23/89
	A18	4,960,720	10/02/90	Shimbo	437	105	08/24/1987
	A19	4,975,252	12/04/90	Nishizawa et al.	422	245	05/26/1989
	A20	5,000,113	03/19/91	Wang et al.	118	723	12/19/86
	A21	5,013,683	05/07/91	Petroff et al.	437	110	01/23/1989
	A22	5,028,565	07/02/1991	Chang, et al.	437	192	08/25/1989
	A23	5,082,798	01/21/92	Arimoto	437	108	09/27/1990
	A24	5,085,885	02/04/92	Foley et al.	477	38	09/10/1990
	A25	5,091,320	02/25/92	Aspnes et al.	437	8	06/15/1990
	A26	5,130,269	07/14/92	Kitahara et al.	437	111	04/25/1989
	A27	5,166,092	11/24/92	Mochizuki et al.	437	105	10/30/1990
<i>Sk</i>	A28	5,173,474	12/22/1992	Connell, et al.	505	1	03/11/1991
Examiner <i>Shawntina Eugene</i>				Date Considered 5/31/04			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.							

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<i>SLF</i>	A29	5,186,718	02/16/93	Tepman et al.	29	25.01	04/15/91
	A30	5,205,077	04/27/93	Wittstock	51	165 R	08/28/91
	A31	5,234,561	08/10/93	Randhawa et al.	204	192.38	08/25/88
	A32	5,246,536	09/21/93	Nishizawa et al.	156	610	03/10/1989
	A33	5,250,148	10/05/93	Nishizawa et al.	156	611	11/12/1991
	A34	5,254,207	10/19/93	Nishizawa et al.	156	601	11/30/1992
	A35	5,256,244	10/26/93	Ackerman	156	613	02/10/1992
	A36	5,259,881	11/09/93	Edwards, et al.	118	719	05/17/91
	A37	5,270,247	12/14/93	Sakuma et al.	437	133	07/08/1992
	A38	5,278,435	01/11/94	Van Hove et al.	257	184	06/08/1992
	A39	5,286,296	02/15/94	Sato et al.	118	719	01/09/92
	A40	5,290,748	03/01/94	Knuutila et al.	502	228	07/16/1992
	A41	5,296,403	03/22/94	Nishizawa et al.	437	133	10/23/1992
	A42	5,300,186	04/05/94	Kitahara et al.	156	613	04/07/1992
	A43	5,311,055	05/10/94	Goodman et al.	257	593	11/22/1991
	A44	5,316,615	05/31/94	Copel	117	95	03/09/1993
	A45	5,316,793	05/31/94	Wallace et al.	427	248.1	07/27/1992
	A46	5,330,610	07/19/94	Eres et al.	117	86	05/28/1993
	A47	5,336,324	08/09/94	Stall et al.	118	719	12/04/1991
	A48	5,338,389	08/16/94	Nishizawa et al.	117	89	04/21/1993
	A49	5,348,911	09/20/94	Jurgensen et al.	117	91	04/26/1993
	A50	5,395,791	03/07/95	Cheng et al.	437	105	10/20/1993
	A51	5,438,952	08/08/1995	Otsuka	117	84	01/31/1994
	A52	5,439,876	08/08/95	Graf et al.	505	447	08/16/1993
<i>SLF</i>	A53	5,443,033	08/22/95	Nishizawa et al.	117	86	03/11/1994
<i>SLF</i>	A54	5,455,072	10/03/95	Bension et al.	427	255.7	11/18/1992
Examiner <i>Shauntina Suga</i>				Date Considered <i>5/31/04</i>			
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<i>SK</i>	A55	5,458,084	10/17/95	Thorne et al.	117	89	12/09/1993
	A56	5,469,806	11/28/95	Mochizuki et al.	117	97	08/20/1993
	A57	5,484,664	01/16/96	Kitahara et al.	428	641	01/21/1994
	A58	5,521,126	05/28/96	Okamura et al.	437	235	06/22/1994
	A59	5,527,733	06/18/96	Nishizawa et al.	437	160	02/18/1994
	A60	5,532,511	07/02/96	Nishizawa et al.	257	627	03/23/1995
	A61	5,540,783	07/30/96	Eres et al.	118	725	05/26/1994
	A62	5,561,735	10/01/1996	Camm	392	416	08/30/1994
	A63	5,580,380	12/03/1996	Liu, et al.	117	86	01/30/1995
	A64	5,601,651	02/11/97	Watabe	118	715	12/14/1994
	A65	5,609,689	03/11/97	Kato et al.	118	719	06/03/96
	A66	5,616,181	04/01/97	Yamamoto et al.	118	723 ER	11/21/1995
	A67	5,637,530	06/10/97	Gaines et al.	114	105	06/10/1996
	A68	5,641,984	06/24/97	Aftergut et al.	257	433	08/19/1994
	A69	5,644,128	07/01/97	Wollnik et al.	250	251	08/25/1994
	A70	5,667,592	09/16/97	Boitnott et al.	118	719	04/16/96
	A71	5,693,139	12/02/97	Nishizawa et al.	117	89	06/15/1993
	A72	5,695,564	12/09/97	Imahashi	118	719	08/03/95
	A73	5,705,224	01/06/98	Murota et al.	427	248.1	01/31/1995
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	A75	5,730,801	03/24/98	Tepman et al.	118	719	08/23/94
	A76	5,730,802	03/24/98	Ishizumi et al.	118	719	12/27/1996
	A77	5,747,113	05/05/98	Tsai	427	255.5	07/29/1996
	A78	5,749,974	05/12/98	Habuka et al.	118	725	07/13/1995
<i>SK</i>	A79	5,788,447	08/04/98	Yonemitsu et al.	414	217	08/05/96
<i>SK</i>	A80	5,788,799	08/04/98	Steger, et al.	156	345	06/11/96
Examiner <i>Shaontea Jaque</i>					Date Considered <i>6/1/04</i>		
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<i>SK</i>	A81	5,801,634	09/01/98	Young et al.	340	635	09/08/97
	A82	5,830,270	11/03/98	McKee et al.	117	106	08/05/1996
	A83	5,850,071	12/15/1998	Makiguchi, et al.	219	390	08/09/1996
	A84	5,851,849	12/22/98	Comizzoli et al.	438	38	05/22/1997
	A85	5,855,675	01/05/99	Doering et al.	118	719	03/03/1997
	A86	5,856,219	01/05/99	Naito et al.	438	241	08/18/97
	A87	5,858,102	01/12/99	Tsai	118	719	02/14/1998
	A88	5,866,213	02/02/99	Foster et al.	427	573	07/19/97
	A89	5,866,795	02/02/99	Wang et al.	73	1.36	03/17/97
	A90	5,882,165	03/16/99	Maydan et al.	414	217	09/10/97
	A91	5,882,413	03/16/99	Beaulieu et al.	118	719	07/11/97
	A92	5,904,565	05/18/1999	Nguyen, et al.	438	687	07/17/1997
	A93	5,923,056	07/13/99	Lee et al.	257	192	03/12/1998
	A94	5,923,985	07/13/99	Aoki et al.	438	301	01/14/1997
	A95	5,925,574	07/20/99	Aoki et al.	437	31	04/10/1992
	A96	5,928,389	07/27/99	Jevtic	29	25.01	10/21/96
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	A98	5,947,710	09/07/1999	Cooper, et al.	418	63	06/16/1997
	A99	5,972,430	10/26/99	DiMeo, Jr. et al.	427	255.32	11/26/1997
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	A101	6,025,627	02/15/00	Forbes et al.	257	321	05/29/1998
	A102	6,036,773	03/14/00	Wang et al.	117	97	03/27/1997
	A103	6,043,177	03/28/00	Falconer et al.	502	4	01/21/1997
	A104	6,046,439	04/04/2000	Johnsgard, et al.	219	444.1	06/16/1997
	A105	6,051,286	04/18/00	Zhao et al.	427	576	08/22/97
<i>SK</i>	A106	6,062,798	05/16/00	Muka	414	416	06/13/96
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<i>SLF</i>	A107	6,071,808	06/06/00	Merchant et al.	438	633	06/23/99
	A108	6,084,302	07/04/00	Sandhu	257	751	12/26/95
	A109	6,086,677	07/11/00	Umotoy et al.	118	715	06/16/98
	A110	6,110,556	08/29/00	Bang, et al.	428	64.1	10/17/97
	A111	6,113,977	09/05/00	Soininen et al.	427	64	09/11/1997
	A112	6,117,244	09/12/00	Bang, et al.	118	715	03/24/98
	A113	6,124,158	09/26/00	Dautartas et al.	438	216	06/08/1999
	A114	6,130,147	10/10/00	Major et al.	438	604	03/18/1997
	A115	6,140,237	10/31/00	Chan et al.	438	687	04/19/99
	A116	6,140,238	10/31/00	Kitch	438	687	04/21/99
	A117	6,143,659	11/07/00	Leem	438	688	08/27/98
	A118	6,144,060	11/07/00	Park et al.	257	310	07/31/98
	A119	6,147,334	11/14/2000	Hannigan	219	544	01/29/1999
	A120	6,151,447	11/21/2000	Moore, et al.	392	418	11/25/1997
	A121	6,158,446	12/12/00	Mohindra et al.	134	25.4	09/04/98
	A122	6,174,809	01/16/2001	Kang, et al.	438	682	12/15/1998
	A123	6,203,613	03/20/2001	Gates, et al.	117	104	10/19/1999
	A124	6,206,967	03/27/01	Mak, et al.	118	666	06/14/00
	A125	6,207,302	03/27/2001	Sugiura, et al.	428	690	03/02/1998
	A126	6,248,605	06/19/2001	Harkonen, et al.	438	29	06/02/1999
	A127	6,271,148	08/07/01	Kao et al.	438	727	10/13/99
	A128	6,287,965	09/11/2001	Kang, et al.	438	648	02/23/2000
	A129	6,291,876	09/18/2001	Stumborg, et al.	257	632	08/20/1998
	A130	6,316,098	11/13/2001	Yitzchaik, et al.	428	339	03/23/1999
✓	A131	2001/0031562	10/18/2001	Raaijmakers, et al.	438	770	02/22/2001
✓✓	A132	2001/0034123	10/25/2001	Jeon, et al.	438	643	04/06/2001
<i>SLF</i>	A133	2001/0041250	11/15/01	Werkhoven et al.	428	212	03/06/01
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Foreign Patent Documents								
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	✓ B2	198 20 147	07/01/1999	DE	H01L	21/3205	<input type="checkbox"/>	<input checked="" type="checkbox"/>
	✓ B3	0 344 352 A1	12/06/1989	EP	H01L	39/24	<input type="checkbox"/>	<input checked="" type="checkbox"/>
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	✓ B5	0 442 490 A1	08/21/1991	EP	C30B	25/02	<input type="checkbox"/>	<input checked="" type="checkbox"/>
	✓ B6	0 799 641 A2	10/08/1997	EP	B01J	20/32	<input type="checkbox"/>	<input checked="" type="checkbox"/>
	✓ B7	2 626 110	07/21/1989	FR	H01L	39/24	<input type="checkbox"/>	<input checked="" type="checkbox"/>
	✓ B8	2 692 597	12/24/1993	FR	C23C	16/00	<input type="checkbox"/>	<input checked="" type="checkbox"/>
	✓ B9	2 298 314 A	08/28/1996	GB	H01L	21/00	<input type="checkbox"/>	<input type="checkbox"/>
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	✓ B12	60-065712 A	04/15/1985	JP	C01B	33/113	<input type="checkbox"/>	<input checked="" type="checkbox"/>
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	✓ B25	63-222421	09/16/1988	JP	H01L	21/205	<input checked="" type="checkbox"/>	<input type="checkbox"/>
	✓ B26	63-227007	09/21/1988	JP	H01L	21/205	<input checked="" type="checkbox"/>	<input type="checkbox"/>
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	B33	64-082615	03/28/1989	JP	H01L	21/205	<input checked="" type="checkbox"/>	<input type="checkbox"/>
	B34	64-082617	03/28/1989	JP	H01L	21/205	<input checked="" type="checkbox"/>	<input type="checkbox"/>
	B35	64-082671	03/28/1989	JP	H01L	29/78	<input checked="" type="checkbox"/>	<input type="checkbox"/>
	B36	64-082676	03/28/1989	JP	H01L	29/80	<input checked="" type="checkbox"/>	<input type="checkbox"/>
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Examiner <i>Shawntina Jugna</i>				Date Considered <i>6/1/04</i>				
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LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT				Applicant Kim, et al.		Confirmation No.: 2911		
(Use several sheets if necessary)				Filing Date		Group		
		Examiner		December 17, 2002		3742		
Foreign Patent Documents								
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Examiner <i>Shawntina - Fugue</i>				Date Considered <i>6/1/09</i>				
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LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT  <i>O I P E</i> <i>U. S. PATENT AND TRADEMARK OFFICE</i> <i>FEB 03 2004</i>				Applicant Kim, et al.	Confirmation No.: 2911			
(Use several sheets if necessary)				Filing Date December 17, 2002	Group 3742			
Examiner <i>Shawntea Juga</i>								
Foreign Patent Documents								
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Examiner <i>Shawntea Juga</i>				Date Considered <i>6/1/04</i>				
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Examiner Shawntea - Suga								
FEB 03 2004 PARENT TRADEMARK OFFICE								
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Examiner Shawntea - Suga				Date Considered 5/31/04				
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(Use several sheets if necessary)				Filing Date December 17, 2002	Group 3742			
Examiner Shawntina Fugua								
Foreign Patent Documents								
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Examiner <i>Shawntina Fugua</i>				Date Considered <i>6/1/04</i>				
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Examiner <i>Shawntina Jugna</i>				Date Considered <i>6/1/09</i>				
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(Use several sheets if necessary)		Filing Date	Group
	Examiner	December 17, 2002	3742
<b>OTHER ART</b>			
*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.	
<i>Stf</i>	C1	Hultman, et al., "Review of the thermal and mechanical stability of TiN-based thin films", <i>Zeitschrift Fur Metallkunde</i> , 90(10) (Oct. 1999), pp. 803-813.	
	C2	Klaus, et al., "Atomic Layer Deposition of SiO <sub>2</sub> Using Catalyzed and Uncatalyzed Self-Limiting Surface Reactions", <i>Surface Review &amp; Letters</i> , 6(3&4) (1999), pp. 435-448.	
	C3	Yamaguchi, et al., "Atomic-layer chemical-vapor-deposition of silicon dioxide films with extremely low hydrogen content", <i>Appl. Surf. Sci.</i> , Vol. 130-132 (1998), pp. 202-207.	
	C4	George, et al., "Surface Chemistry for Atomic Layer Growth", <i>J. Phys. Chem.</i> , Vol. 100 (1996), pp. 13121-131.	
	C5	George, et al., "Atomic layer controlled deposition of SiO <sub>2</sub> and Al <sub>2</sub> O <sub>3</sub> using ABAB...binary reaction sequence chemistry", <i>Appl. Surf. Sci.</i> , Vol. 82/83 (1994), pp. 460-467.	
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Examiner	<i>Shawntina Fugua</i>		Date Considered <i>5/31/04</i>
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U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)		Docket No. AMAT/5163P1/DISP LAY/AHRDWR/RKK	Serial No. 10/321,289
<b>LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT</b>		Applicant Kim, et al.	Confirmation No.: 2911
(Use several sheets if necessary)		Filing Date December 17, 2002	Group 3742
Examiner <i>Shawntina Fugue</i> FEB 03 2004 PATENT & TRADEMARK OFFICE			
<b>OTHER ART</b>			
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<i>Sh</i>	C18	Min, et al., "Chemical Vapor Deposition of Ti-Si-N Films with Alternating Source Supply", <i>Mat., Res. Soc. Symp. Proc.</i> , Vol. 564 (Apr. 5, 1999), pp. 207-210	
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	C29	Solanki, et al., "Atomic Layer deposition of Copper Seed Layers", <i>Electrochemical and Solid State Letters</i> , 3(10) (2000), pp. 479-480	
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<i>Sh</i>	C33	Abstracts of articles re atomic layer deposition	
Examiner <i>Shawntina Fugue</i>		Date Considered	<i>5/31/04</i>
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<b>OTHER ART</b>			
*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.	
<i>Shawntea Fugue</i>	C34	Abstracts of search results re atomic layer deposition, search dated January 24, 2002	
	C35	Abstracts of articles re atomic layer deposition and atomic layer nucleation	
	C36	Abstracts of articles re atomic layer deposition and semiconductors and copper	
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<i>✓</i>	C43	Kitigawa, et al., "Hydrogen-mediated low temperature epitaxy of Si in plasma-enhanced chemical vapor deposition", Applied Surface Science (2000), pp. 30-34	
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LIST OF RELATED CASES

<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Inventor/Applicant</u>
219288US2 PCT*	10/049,293	04/30/02	ITO, et al.
246590US90 DIV	10/732,296	12/11/03	ITO, et al.
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Stf 219288US2PCT*	10/049,293	04/30/02	ITO, et al.
Stf 242768US90 CONT	10/663,681	09/17/03	ITO, et al.

Maristina - Inga 6/1/04